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PATENT

Attorney Docket No.: 1332/US/1

Express Mail Label No.: EV 423776544 US

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of:

Applicant

: Cacka et al.

Appln. No.

: 10/045,953

Filed

January 12, 2002

Title

TOOTHBRUSH

Confirmation No.: 2740

Group Art Unit: 1744

Examiner: Not Yet Assigned

CERTIFICATE OF MAILING BY EXPRESS MAIL

MAIL STOP AMENDMENT Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

Sir:

The undersigned hereby certifies that the following documents:

- 1. Supplemental Information Disclosure Statement (2 pages);
- 2. Form PTO-1449 (5 pages);
- 3. Copies of One Hundred and Seventy-five (175) References;
- 4. Certificate of Mailing by Express Mail (1 page); and
- 5. Return Card

relating to the above application, were deposited as "Express Mail" under 37 CFR § 1.10, Mailing Label No. EV 423776544 US, with the United States Postal Service addressed to Mail Stop Amendment, Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450 on December 16, 2004.

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EV423776544US

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Examiner: Till, Terrence R.

SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT UNDER 37 C.F.R. §§1.97(b)(4) and 1.98

MAIL STOP AMENDMENT Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

Sir:

The Examiner is requested to consider the references noted on the enclosed Form PTO-1449 during examination of the above-identified patent application. These references are submitted for the Examiner's consideration and are submitted pursuant to the duty of disclosure under 37 C.F.R. § 1.56. In submitting these references, no representation is made or implied that the references are or are not material to the examination of the application. The Examiner is encouraged to make his or her own determination of materiality. Copies of all the cited art documents are provided herewith.

This IDS is being filed before the first Office action, after the filing of a Request for Continued Examination. Accordingly, pursuant to 37 C.F.R. § 1.97(b)(4), no fees are due with respect to this filing. However, should any such fees or petitions be required, please consider this a request therefor and authorization to charge Deposit Account No. 04-1415 as necessary.

Should the Examiner have any questions, please contact the undersigned attorney.

Dated: 16 DEEMER 2004.

Respectfully submitted,

S. Craig Hemenway, Registration No. 44,759 Attorney for Applicant USPTO Customer No. 20686

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Tel: 303-629-3400 Fax: 303-629-3450 FORM PTO-1449 U.S. DEPARTMENT OF COMMERCE (Modified) PATENT AND TRADEMARK OFFICE COMMERCE (MODIFICE COMMERCE)

INFORMATION DISCLOSURE STATEMENT BY APPLICANT DEC 1 6 2004

(Use several sheets if necessary)

ATTY. DOCKET NO. 1332/US/1	APPLN. NO. 10/045,953	
APPLICANT: Cacka et al.		
FILING DATE January 12, 2002	ART UNIT 1744	· · ·

EXAMINER	1	PATENT	ISSUE	·			FILING DATE IF
INITIAL		NUMBER	DATE	PATENTEE	CLASS	SUBCLASS	APPROPRIATE
	1.	5,864,911	02/1999	Arnoux			
	2.	5,901,397	05/1999	Hafele et al.			
	3.	5,934,908	08/1999	Woog et al.			
,	4.	6,026,828	02/2000	Altshuler			
	5.	6,092,252	07/2000	Fischer et al.			
	6.	6,106,294	08/2000	Daniel			
· · · · · · · · · · · · · · · · · · ·	7.	6,138,310	10/2000	Porper et al.			
	8.	6,140,723	10/2000	Matsui et al.			
	9.	6,148,462	11/2000	Zseng			
	10.	6,154,912	12/2000	Li			
	11.	6,178,579	01/2001	Blaustein et al.			
	12.	6,195,828	03/2001	Fritsch			
- 	13.	6,202,242	03/2001	Salmon et al.			
	14.	6,203,320	03/2001	Williams et al.			
	15.	6,230,354	05/2001	Sproat			
****	16.	6,230,717	05/2001	Marx et al.			
	17.	6,237,178	05/2001	Krammer et al.			
-	18.	6,308,358	10/2001	Gruber et al.			
	19.	6,308,359	10/2001	Fritsch et al.	-		
	20.	6,341,400	01/2002	Kobayashi et al.			
	21.	6,343,396	02/2002	Simovitz et al.			
	22.	6,343,400	02/2002	Massholder et al.			
	23.	6,347,425	02/2002	Fattori et al.			
	24.	6,353,956	03/2002	Berge			
	25.	6,360,395	03/2002	Blaustein et al.			
	26.	6,363,565	04/2002	Paffrath			
	27.	6,367,108	04/2002	Fritsch et al.			
	28.	6,374,448	04/2002	Seifert			
	29.	6,381,795	05/2002	Hofmann et al.			
	30.	6,401,288	06/2002	Porper et al.			
	31.	6,421,865	07/2002	McDougall			
	32.	6,421,866	07/2002	McDougall			
	33.	6,421,867	07/2002	. Weihrauch			
	34.	6,434,773	08/2002	Kuo			
	35.	6,446,294	09/2002	Specht			
	36.	6,446,295	09/2002	Calabrese			
	37.	6,453,497	09/2002	Chiang et al.			



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INITIAL		NUMBER	DATE	PATENTEE	CLASS	SUBCLASS	APPROPRIATE
	38.	6,453,498	09/2002	Wu			
	39.	6,453,499	09/2002	Leuermann			
	40.	6,463,615	10/2002	Gruber et al.			
	41.	6,490,747	12/2002	Metwally			
	42.	6,510,575	01/2003	Calabrese			
	43.	6,536,066	03/2003	Dickie			
	44.	6,564,940	05/2003	Blaustein et al.			
	45.	6,574,820	06/2003	DePuydt et al.			
	46.	6,581,233	06/2003	Cheng			
	47.	6,581,234	06/2003	Lee et al.			
	48.	6,588,042	07/2003	Fritsch et al.			
	49.	6,599,048	07/2003	Kuo			
	50.	6,622,333	09/2003	Rehkemper et al.			
	51.	6,647,577	11/2003	Tam			
	52.	6,654,979	12/2003	Calabrese			
	53.	6,665,901	12/2003	Driesen et al.			
	54.	6,691,363	02/2004	Huen			
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	56.	6,721,986	04/2004	Zhuan			
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	58.	6,735,803	05/2004	Kuo			
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	60.	6,739,012	05/2004	Grez et al.			
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	62.	6,760,945	07/2004	Ferber et al.			
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-	66.	6,779,126	08/2004	Lin et al.			
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	68.	6,785,926	09/2004	Green			
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	70.	6,795,993	09/2004	Lin			
	71.	6,798,169	09/2004	Stratmann et al.			
	72.	6,799,346	10/2004	Jeng et al.			
	73.	6,802,097	10/2004	Hafliger et al.			
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	76.	2001/0016963	08/2001	Driesen et al.			
*****	77.	2002/0017474	02/2002	Blaustein et al.			
**	78.	2002/0029988	03/2002	Blaustein et al.			
	79.	2002/0032941	03/2002	Blaustein et al.			
	·80.	2002/0039720	04/2002	Marx et al.			
	81.	2002/0066147	06/2002	Schutz			
	82.	2002/0078514	06/2002	Blaustein et al.			
	83.	2002/0084707	07/2002	Tang			
	84.	2002/0088068	07/2002	Levy et al.			
	85.	2002/0095734	07/2002	Wong			
	86.	2002/0100134	08/2002	Dunn et al.			
	87.	2002/0108193	08/2002	Gruber			
	88.	2002/0116775	08/2002	Wong			
	89.	2002/0129454	09/2002	Hilscher et al.			
	90.	2002/0138926	10/2002	Brown, Jr. et al.			
	91.	2002/0152563	10/2002	Sato			
No.	92.	2002/0152564	10/2002	Blaustein et al.			
	93.	2002/0162180	11/2002	Blaustein et al.			
	94.	2002/0166188	11/2002	Driesen et al.			
	95.	2002/0174498	11/2002	Li			
	96.	2002/0184719	12/2002	Eliav et al.			
	97.	2003/0033679	02/2003	Fattori et al.			<u> </u>
- ***	98.	2003/0033680	02/2003	Davies et al.			
	99.	2003/0041396	03/2003	Dickie			
	100.	2003/0041397	03/2003	Hafemann			
	101.	2003/0066145	04/2003	Prineppi			
	102.	2003/0074751	04/2003	Wu			
 -	103.	2003/0079305	05/2003	Takahata et al.			
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	109.	2003/0101526	06/2003	Hilscher et al.			
	110.	2003/0106175	06/2003	Lam			
	111.	2003/0126699	07/2003	Blaustein et al.			
	112.	2003/0131427	07/2003	Hilscher et al.			
	113.	2003/0140435	07/2003	Eliav et al.			
	114.	2003/0140436	07/2003	Gatzemeyer et al.			
	115.	2003/0140437	07/2003	Eliav et al.			
	116.	2003/0154567	08/2003	Drossler et al.			
	117.	2003/0154568	08/2003	Boland et al.			
	118.	2003/0163881	09/2003	Driesen et al.			
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	120.	2003/0182743	10/2003	Gatzemeyer et al.		***	
	121.	2003/0182744	10/2003	Fattori et al.			
	122.	2003/0182746	10/2003	Fattori et al.			
	123.	2003/0192139	10/2003	Fattori et al.			
	124.	2003/0196283	10/2003	Eliav et al.			
	125.	2003/0204925	11/2003	Hall et al.			
	126.	2003/0213075	11/2003	Hui et al.			
-	127.	2003/0213076	11/2003	Schutz et al.			
	128.	2003/0221267	12/2003	Chan			
	129.	2003/0221269	12/2003	Zhuan			
****	130.	2003/0226223	12/2003	Chan			
	131.	2004/0010869	01/2004	Fattori et al.			
	132.	2004/0010870	01/2004	McNair			
	133.	2004/0010871	01/2004	Nishinaka et al.			
	134.	2004/0010872	01/2004	Chiang			
	135.	2004/0016067	01/2004	Kraemer			
	136.	2004/0016068	01/2004	Lee			
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	138.	2004/0019987	02/2004	Chu			
,	139.	2004/0025274	02/2004	Moskovich et al.			
	140.	2004/0034951	02/2004	Davies et al.			
	141.	2004/0045106	03/2004	Lam			
	142.	2004/0045107	03/2004	Egeresi			
	143.	2004/0049867	03/2004	Hui			
	144.	2004/0049868	03/2004	Ng			
	145.	2004/0060132	04/2004	Gatzemeyer et al.			
	146.	2004/0060134	04/2004	Eliav et al.			
	147.	2004/0060135	04/2004	Gatzemeyer et al.			
	148.	2004/0060136	04/2004	Gatzemeyer et al.			
	149.	2004/0060137	04/2004	Eliav			
	150.	2004/0068811	04/2004	Fulop et al.			ļ
	151.	2004/0074026	04/2004	Blaustein et al.			
	152.	2004/0083566	05/2004	Blaustein et al.			
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	154.	2004/0088806	05/2004	DePuydt et al.			
	155.	2004/0088807	05/2004	Blaustein et al.			
	156.	2004/0091834	05/2004	Rizoiu et al.			
	157.	2004/0107521	06/2004	Chan et al.			
	158.	2004/0123409	07/2004	Dickie			
	159.	2004/0128777	07/2004	Koh			
	160.	2004/0128778	07/2004	Wong			
	161.	2004/0128779	07/2004	Chan et al.			
	162.	2004/0128780	07/2004	Chan	_		
	163.	2004/0134001	07/2004	Chan	1		

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	164.	2004/0143917	07/2004	Ek			
	165.	2004/0154112	08/2004	Braun et al.			<u> </u>
	166.	2004/0154113	08/2004	Drossler et al.			
	167.	2004/0158944	08/2004	Fattori			
·-	168.	2004/0163191	08/2004	Cuffaro et al.			
	169.	2004/0168269	09/2004	Kunita et al.			
) .	170.	2004/0168270	09/2004	Choi et al.			
	171.	2004/0168271	09/2004	McDougall			
	172.	2004/0168272	09/2004	Prineppi			
	173.	2004/0177458	09/2004	Chan et al.			
	174.	2004/0187889	09/2004	Kemp et al.			
	175.	2004/0200016	10/2004	Chan et al.			

	FOREIGN PAT	ENT OR PUBLISHE	ED FOREIGN PATE	NT APPLICA	TION		
EXAMINER INITIAL	DOCUMENT NUMBER	PUBLISHED DATE	COUNTRY	CLASS	SUBCLASS	TRANS	LATION NO
	1					L	

OTHER DOCUME	NTS (Including Author, Title, Date, Pertinent Pages, Etc.)
EXAMINER INITIAL	
EXAMINER	DATE CONSIDERED
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conformance and not considered. Include copy of this form with next communication to applicant.